IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): MAMITSU et al.

Atty. Dkt.: 01-103-CON3

Serial No.: Unknown

Group Art Unit:

Filed: Concurrently herewith

Examiner:

Title: SEMICONDUCTOR DEVICE

HAVING RADIATION

STRUCTURE

Date: November 4, 2003

Commissioner for Patents Arlington, VA 22202

INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to 37 C.F.R. §1.56, the reference(s) listed on the attached Form PTO-1449 is/are being submitted for consideration by the Examiner without any admission that it/they constitute(s) statutory prior art, or without any admission that it/they contain(s) subject matter that anticipates the invention or renders the invention obvious to a person of ordinary skill in the art.

The Examiner is requested to initial the attached PTO Form-1449 and to return a copy of same to the undersigned attorney as proof that the listed reference(s) has/have been considered and made of record.

Respectfully submitted,

David G. Posz Reg. No. 37,701

Posz & Bethards, PLC 11250 Roger Bacon Drive, Suite 10 Reston, VA 20190 (703)707-9110 (phone) Customer No. 23400

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	APPLICANT	MAMITSU et a	ı l.	
	FILING DATE	Nov. 4, 2003	GROUP	

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
de la companya della	5,708,299	Jan. 13, 1998	Teramae et al		
Do l	6,072,240	June 6, 2000	Kimura et al		
88	5,248,853	Sep. 28, 1993	Ishikawa et al		
BI	5,801,445	Sep. 1, 1998	Ishihara et al		
R	5,229,646	Jul. 20, 1993	Tsumura		
Of I	4,558,345	Dec. 10, 1985	Dwyer et al		
SP	4,546,374	Oct. 8, 1985	Olsen et al		
as	4,984,061	Jan. 8, 1991	Matsumoto		
OF	5,481,137	Jan 2, 1996	Harada et al.		
RB	4,827,082	May 2, 1989	Horiuchi et al		
RP	4,538,170	Aug. 27, 1985	Yerman		

FOREIGN PATENT DOCUMENTS

							TRANSL	ATION
	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
08	EP0660396	12/24/93	Europe					
No	EP0450980	4/05/91	Europe					
PP	6-291223	10/94	JAPAN					
PB	3-20067	01/91	JAPAN					
6	2146174	11/85	GB					

Takamura, "Electronic Technology", pp. 56-59 (1999-5).
Johnson et al., "Silicon Precipitate Nodule-Induced Failures of MOSFETS", ISTFA '91 (Nov. 11-15, 1991), pp. 161-165.
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FORM PTO-1449	ATTY. DKT NO.	1-103-CON3	SER. NO.
	APPLICANT	MAMITSU et al.	
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REFERENCE DESIGNATION

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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
026)	4,646,129	Feb. 24, 1987	Yerman et al		
921	4,141,030	Feb. 20, 1979	Eisele et al		
6/2	6,448,645	Sep. 10, 2002	Kimura		
PS	6,538,308	Mar. 25, 2003	Nakase		
M	6,380,622	Apr. 30, 2002	Hirai		
no	09/675,209	Filed Sept. 29, 2000	Suzuki		
Pr	5,221,851	Jun. 22, 1993	Gobrecht et al.		

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	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
Po	4-249353	9/92	JAPAN					
Ro	11-260979	09/99	JAPAN					
B	4-27145	01/92	JAPAN					
Do	9-148492	06/97	JAPAN					
As	4-12555	01/92	JAPAN					
R	4-103150	04/92	JAPAN					
M	60-137042	07/85	JAPAN					
Ry	5-109919	04/93	JAPAN					
Ro	61-166051	07/86	JAPAN					
R	2-117157	05/90	JAPAN					
RP	63-102326	05/88	JAPAN					

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R	5,990,550	Nov. 23, 1999	Umezawa		
028	5,608,610	Mar. 4, 1997	Brzezinski		
130	5,396,403	Mar. 7, 1995	Patel		
TP.	5,293,301	Mar. 8, 1994	Tanaka et al.		
R	5,641,997	June 24, 1997	Ohta et al.		
RP	5,789,820	Aug. 4, 1998	Yamashita		

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020	60-235430	11/85	JAPAN						
010	07-240432	9/95	JAPAN						
68	8-45874	2/96	JAPAN				-		
PP	60-95947	05/85	JAPAN				· · ·		
620	61-265849	11/86	JAPAN						
M	62-141751	06/87	JAPAN						
026	63-096946	04/88	JAPAN						
No	62-92349	4/87	JAPAN				. •		
Po	62-287649	12/87	JAPAN						
OP	59-38734	09/84	JAPAN						
as	01-228138	09/89	JAPAN						
M	54-40569	03/79	JAPAN						
By	61-251043	11/86	JAPAN						
A	54-95183	07/79	JAPAN		• • • • • • • • • • • • • • • • • • • •			1	

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100	2002/0158333	Oct. 31, 2002	Teshima		
926	S/N 10/201556	July 24, 2002	Hirano et al.		
05	5726466	March 10, 1998	Nishitani		
Do	4,470,063	Sep. 4, 1984	Arakawa et al.		
DR	5,708,299	Jan. 13, 1998	Teramae et al		

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20	59-031042	02/84	JAPAN					
900	07-038013	02/95	JAPAN			-		
120	07-273276	10/95	JAPAN					
978	08-191145	07/96	JAPAN					
121	2000-91485	03/00	JAPAN .					
020	W098/12748	3/26/98	PCT					
Po	JP-A-5-283562 *	10/29/93	JAPAN				х	
Ro	JP-A-6-349987 *	12/22/94	JAPAN				х	
R	JP-A-7-45765 *	2/14/95	JAPAN				х	
R	JP-A-11-186469 *	7/9/99	JAPAN				х	
M	JP-A-2000-31351 *	1/28/00	JAPAN				х	
820	JP-A-2001-118961 *	4/27/01	JAPAN			 -	х	

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